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## **Microbeam analysis — Electron probe microanalysis — Guidelines for qualitative point analysis by wavelength dispersive X-ray spectrometry**

*Analyse par microfaisceaux — Analyse par microsonde électronique  
(Microsonde de Castaing) — Lignes directrices pour l'analyse  
qualitative ponctuelle par spectroscopie de rayons X à dispersion de  
longueur d'onde*



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## Contents

Page

Foreword .....	iv
Introduction .....	v
1 Scope.....	1
2 Normative references .....	1
3 Terms and definitions .....	1
4 Abbreviated terms.....	2
5 Apparatus.....	2
6 Procedure for identification .....	2
6.1 General .....	2
6.2 Setting of analysis conditions .....	2
6.3 Method for analysing an X-ray spectrum .....	4
6.4 Detection limit .....	5
7 Test report.....	6
Annex A (informative) Example of the test report on qualitative analysis of a stainless steel sample by EPMA .....	7
Bibliography .....	10

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## Foreword

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## Introduction

Electron probe microanalysis is used to qualitatively identify the elements present in a specimen on a micrometric scale. It is necessary to specify the measurement conditions and identification method in order to avoid reporting erroneous or inconsistent results.